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An Oscillator-Based True Random Number Generator with Process and Temperature Tolerance

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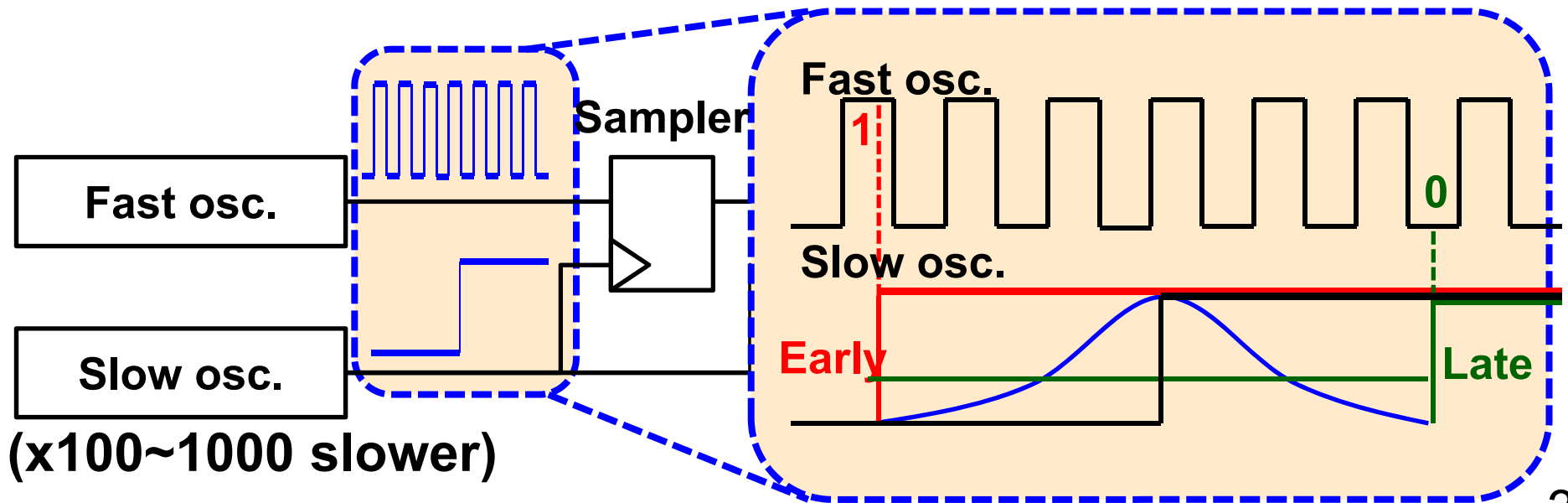
Security and random number

- **Cryptography and authentication system requires **unpredictable random numbers.****
ex.) Private/Public key generation,
challenge-and-response authentication, etc.
- **Random number generator**
 - **Pseudo random number generator**
 - **Mathematical calculation**
 - **Output is **periodic and then predictable.****
 - **True random number generator (TRNG)**
 - **Physical random source**
 - **Output is **unpredictable.****

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Oscillator-based TRNG

- Acquires randomness from period jitters of oscs.
- **Pro: Easy to implement**
- **Con: Difficult to generate highly random numbers**
 - sensitive to duty cycle of fast osc.



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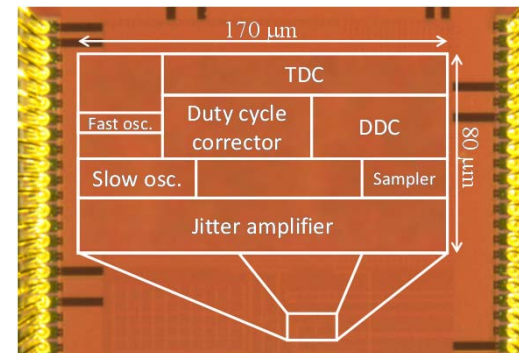
Duty cycle of fast osc. decides 0/1 probability.

Contribution

- **Duty cycle variation due to temperature**
 - Biases 0/1 probability beyond **$50 \pm 0.125\%$** and makes TRNG fail in NIST randomness test.
 - **Cannot be eliminated by static tuning at shipping test**



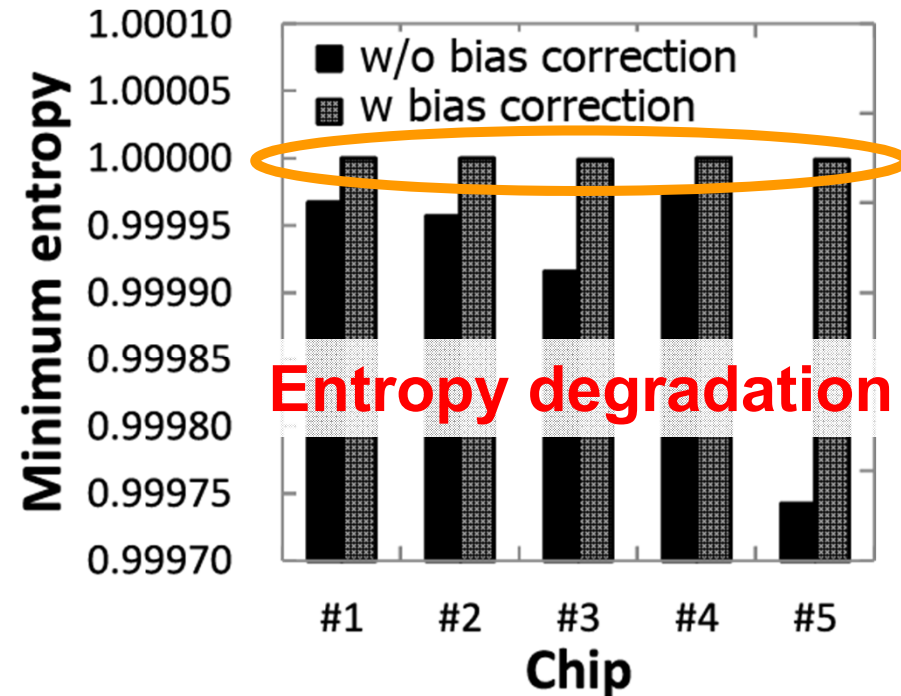
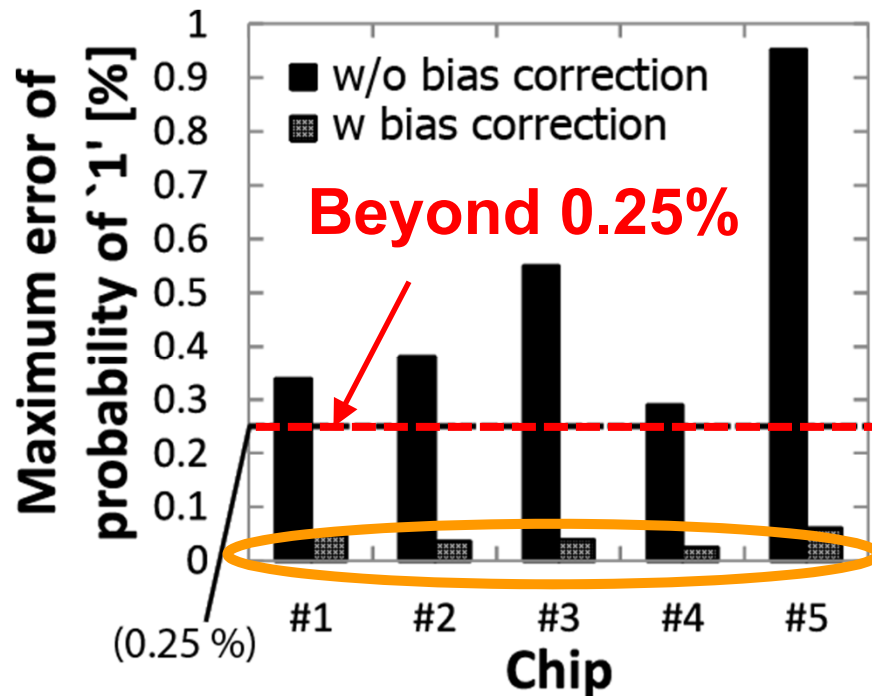
- **Developed a TRNG w/ dynamic 0/1 bias correction for process and temperature tolerance**
 - Fast duty cycle monitor
 - Duty cycle adjuster



65nm
CMOS

Dynamic duty cycle correction

- **Proposed duty cycle correction** sustained duty cycle and entropy under temperature variation between 0°C and 75°C.
 - **Without it**, duty cycle and entropy degraded.



Comparison w/ existing works

- Among TRNGs that pass NIST tests, area of proposed TRNG is minimum.

	Bucci 2013 [11]	Bucci 2008 [3]	Pareschi 2010 [12]	Srinivasan 2010 [2]	This work
Type	Direct amp.	Osc.	Chaos	Metastable	Osc.
Tech.	180nm	90nm	180nm	45nm	65nm
Area (45nm)	1,563 μm^2	3,250 μm^2	7,875 μm^2	4,004 μm^2	3,335μm^2
Randomness test	FIPS140-1 Knuth	AIS31 Entropy	NIST	NIST Entropy Auto corr. Run length	NIST DIEHARD